Docket No.

217830US0CONT

# IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF:

Yasuyo SAITO, et al.

SERIAL NO:

**NEW APPLICATION** 

GAU:

FILED:

HEREWITH

EXAMINER:

FOR:

ORGANIC METAL COMPLEX, INFRARED-ABSORBING DYE AND INFRARED ABSORPTION FILTER CONTAINING IT, AND FILTER FOR PLASMA DISPLAY PANEL

**INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97** 

ASSISTANT COMMISSIONER FOR PATENTS WASHINGTON, D.C. 20231

SIR:

Applicant(s) wish to disclose the following information.

#### REFERENCES

- The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

### RELATED CASES

- Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check is attached in the amount required under 37 CFR §1.17(p).

# **CERTIFICATION**

- Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

### DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check is enclosed herewith, or credit any overpayment to deposit account number <u>15-0030</u>. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

OBLON, SPIVAK, McCLELLAND, MAIER & NEUSTADT, P.C.

Norman F. Oblon

Registration No.

24,618

William E. Beaumont

Registration No.

30,996

22950

Tel. (703) 413-3000 Fax. (703) 413-2220 (OSMMN 10/01)

Form PTO 1449		U.S. DEPARTMENT	OF COMMERCE	ATTY DOCKET NO. 217830US0CONT		SERIAL	SERIAL NO.	
(Modified)		PATENT AND TRAC	DEMARK OFFICE			NEW APPLICATION		
				APPLICANT			.89	
LIST OF	REFE	RENCES CITED BY AP	PLICANT	Yas	uyo SAITO,	et al.		
			FILING DATE		GROUP 19			
			HEREWITH		10,5			
				U.S. PATENT DOCUMENTS			ů =	
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE	
	AA	5,804,102	09/08/98	OI ET AL				
	AB							
	AC							
	AD							
	AE							
	AF							
	AG							
	АН				-			
	Al							
	AJ							
	AK						<del></del>	
	AL						-	
	AM						· · · · · · · · · · · · · · · · · · ·	
	AN							
			FO	REIGN PATENT DOCUMENTS	<del></del>			
	DOGUMENT.							
	J	NUMBER	DATE	COUNTRY		YES	TRANSLATION	
	AO	63-112592	05/17/88	JAPAN		100	NO XX	
	AP	4-174402	06/22/92	JAPAN			XX	
	AQ	6-38124	05/18/94	JAPAN			XX	
	AR	2-4881	01/30/90	JAPAN			XX	
	AS	<del></del>	1					
	AT							
	AU	,						
	AV		1	No. 1		~		
		OTHER RE	EEDENCES (I	ncluding Author, Title, Date, Pertin		- \		
	—т			ARBON BOND FORMTION IN HELIC	-	•	=	
	AW	(PHENYLMETHYLIDEN	NEAMINE) BEI	NZENETHIOLATO] NICKEL (II)", CH	IEMISTRY LET	ITERS, 19	92, NO. 5, PP. 893-896	
	AX	T. KAWAMOTO ET AL, "VALENCE ISOMERIZATION. SYNTHESIS AND CHARACTERIZATION OF COBALT AND NICKEL COMPLEXES WITH NON-INNOCENT N2S2 LIGAND", BULL. CHEM. SOC. JPN., 1997, VOL. 70, NO. 7, PP. 1599-1606  T. KAWAMOTO ET AL, "SYNTHESIS AND CHARACTERIZATION OF THE PLATINUM COMPLEXES WITH N,S OR C,N,S						
	AY	T. KAWAMOTO ET AL, LIGANDS DERIVED FR	"SYNTHESIS COM 2-PHENY	AND CHARACTERIZATION OF THE LENZOTHIAZOLINE", INORG. CH	E PLATINUM ( IIM. ACTA, 199	COMPLEX 37, VOL. 20	ES WITH N,S OR C,N,S 65, NO. 1-2, PP. 163-167	
	AZ				Additi	onal Refer	rences sheet(s) attached	
Examiner					Date Cons	Date Considered		
*Examiner: Init conformance a	ial if re ind not	ference is considered, w considered. Include cor	hether or not by of this form	citation is in conformance with MPEP with next communication to applicant	° 609; Draw line	e through o	citation if not in	